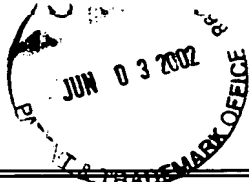


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 217474US0		SERIAL NO. 10/025,653	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kenji YAMAMOTO, et al.			
				FILING DATE December 26, 2001		GROUP 1755	
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA	6,033,734	03/07/2000	Wolf-Dieter MUENZ, et al.			
	AB	6,071,560	06/06/2000	H. BRAENDLE, et al.			
	AC	5,126,030	06/30/92	H. TAMAGAKI, et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AD	9-256138	09/30/97	JAPAN (with English translation)			
	AE	4-128363	04/28/92	JAPAN (with English Abstract)			X
	AF	7-188901	07/25/95	JAPAN (with English translation)			
	AG	7-197235	08/01/95	JAPAN (with English translation)			
	AH	7-237010	09/12/95	JAPAN (with English translation)			
	AI	7-310174	11/28/95	JAPAN (with English translation)			
	AJ	8-209335	08/13/96	JAPAN (with English translation)			
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	AL	9-256138	09/30/97	JAPAN (with English translation)			
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	AN	9-323205	12/16/97	JAPAN (with English translation)			
	AO	10-025566	01/27/98	JAPAN (with English translation)			
	AP	10-251831	09/22/98	JAPAN (with English translation)			
	AQ	11-006056	01/12/99	JAPAN (with English translation)			
	AR	11-036063	02/09/99	JAPAN (with English translation)			
	AS	11-131215	05/18/99	JAPAN (with English translation)			
	AT	11-131216	05/18/99	JAPAN (with English translation)			
	AU	2000-038653	02/08/2000	JAPAN (with English translation)			
	AV	2000-144376	05/26/2000	JAPAN (with English translation)			
	AW	2000-328236	11/28/2000	JAPAN (with English translation, corr. USSN 09/480,164)			
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	BB	2901049 (8-134635)	06/02/99	JAPAN (with English translation)			
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	BC	A. KIMURA, et al., Surface and Coatings Technology, vol. 120-121, pages 438-441, "EFFECTS OF Al CONTENT ON HARDNESS, LATTICE PARAMETER AND MICROSTRUCTURE OF Ti _{1-x} Al _x N FILMS", 1999					
	BD	A. SUGISHIMA, et al., Surface and Coatings Technology, vol. 97, pages 590-594, "PHASE TRANSITION OF PSEUDOBINARY Cr-Al-N FILMS DEPOSITED BY MAGNETRON SPUTTERING METHOD", 1997					
Examiner					Date Considered		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

CORRECTED Form PTO 1449 (Modified)			U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 217474US0		SERIAL NO. 10/025,653	
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<i>g</i>	AA	6,033,734	03/07/2000	Wolf-Dieter MUENZ, et al.	—	✓			
<i>g</i>	AB	6,071,560	06/06/2000	H. BRAENDLE, et al.	—	✓			
<i>g</i>	AC	5,126,030	06/30/92	H. TAMAGAKI, et al.	—	✓			
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Examiner <i>g</i>					Date Considered 6/15/03				

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	AB	6,033,768	03/07/2000	W -D. MUENZ, et al.	✓	✓	
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	AM	Patent Abstract of Japan, JP 08-120445, May 14, 1996					
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	AO	Steven. R. LAMPMAN, et al., ASM International, Metals Handbook, vol. 2, Tenth Edition, XP-002203070, page 1096, " PROPERTIES AND SELECTION: NONFERROUS ALLOYS AND SPECIAL-PURPOSE MATERIALS", 1990					
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						<input type="checkbox"/> Additional References sheet(s) attached	
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[Signature]				6/15/03			
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LIST OF REFERENCES CITED BY APPLICANT

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01	AA	6,296,928	10/02/01	YAMADA, et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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Date Considered

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